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ILNAS-EN IEC 61788-17:2021

Superconductivity - Part 17: Electronic characteristic measurements - Local critical current density and its distribution in large-area

Supraleitfähigkeit - Teil 17: Messungen
der elektronischen Charakteristik -
Lokale kritische Stromdichte und deren
Verteilung in großflächigen

Supraconductivité - Partie 17: Mesures de
caractéristiques électroniques - Densité
de courant critique local et sa
distribution dans les films

06/2021



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amendments and corrigenda (if any)

English Version

**Superconductivity - Part 17: Electronic characteristic
measurements - Local critical current density and its distribution
in large-area superconducting films
(IEC 61788-17:2021)**

Supraconductivité - Partie 17: Mesures de caractéristiques
électroniques - Densité de courant critique local et sa
distribution dans les films supraconducteurs de grande
surface
(IEC 61788-17:2021)

Supraleitfähigkeit - Teil 17: Messungen der elektronischen
Charakteristik - Lokale kritische Stromdichte und deren
Verteilung in großflächigen supraleitenden Schichten
(IEC 61788-17:2021)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 90/462/FDIS, future edition 2 of IEC 61788-17, prepared by IEC/TC 90 "Superconductivity" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61788-17:2021.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2022-03-02
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2024-06-02

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Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-815	-	International Electrotechnical Vocabulary - Part 815: Superconductivity	-	-



INTERNATIONAL STANDARD



**Superconductivity –
Part 17: Electronic characteristic measurements – Local critical current density
and its distribution in large-area superconducting films**

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